CURRICULUM VITAE

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Years of teaching at college level: 19 Years
Years of teaching at Lamar: 22 Years

EDUCATION:

- Ph.D. in Electrical and Computer Engineering, (1996-2000),
  Vanderbilt University, Nashville, TN, USA
- M. Sc. in Electrical and Computer Engineering, (1994-1996).
  Pennsylvania State University, State College, PA, USA

PROFESSIONAL EXPERIENCE

▪ August 2017- Present	Professor Department of Electrical Engineering Lamar University, Beaumont TX
▪ August 2009- August 2017	Associate Professor Department of Electrical Engineering Lamar University, Beaumont TX
▪ June 2003- August 2009	Assistant Professor Department of Electrical Engineering Lamar University, Beaumont TX
▪ February 2001- May 2003	Department Chair Electronics & Computer Education Department Pamukkale University, Denizli, TURKEY
▪ September 2000- May 2003	Assistant Professor Electronics & Computer Education Department Pamukkale University, Denizli, TURKEY

TEACHING INTERESTS

Online Teaching, Web-based learning

Online labs, Integrating Lab experiences into Theory courses

Study Abroad opportunities

RESEARCH EXPERTISE

Radiation Effects Modeling in Integrated Circuits

Low Power Design & Reliability Analysis

Interconnect Noise & Delay Prediction and Modeling

Contactless VLSI Testing

HONORS, AWARDS, AND APPOINTMENTS

- **Distinguished Faculty Teaching Fellow**, Lamar University (2018-2021)
- Nominated for the **TSUS Regents' Teacher Award**, with nominations from the College, University, and President, in 2022 and 2023.
- **Associate Editor** for *International Journal of Electronics* (2008-present)
- Corresponding Editor for *IEEE Potentials* (2008)
- Research Enhancement Grant Awards obtained from Lamar University
- Promoted to Department Chair position, Electronics & Computer Education Department, Pamukkale University, Denizli, TURKEY, Feb 2001- May 2003.
- Teaching and Research Assistantships awarded from Vanderbilt University (1999), (1998).
- Graduated first in rank among the graduates of Gazi University Electronics Dept, Summer of 1990.
- In the Science Weighted scoring, scored among the top 1% entrants in nation-wide university entrance Exam in Turkey. Nearly 500,000 students had taken the exam.

PUBLICATIONS:

Authored 3 books, 2 book chapters and published 30 refereed journal articles that include special feature articles. Some papers appeared on journal covers. I have also presented at many conferences which include international.

BOOK PUBLICATIONS

1. Sayil, S., "*Noise Contamination in Nanoscale VLSI Circuits*"- Synthesis Lectures on Digital Circuits & Systems, Springer Publishing, NY, September, **2022** (https://doi.org/10.1007/978-3-031-12751-9). This book provided an overview on various noise sources that impact performance and reliability in microchips.
2. Sayil, S. "*Contactless Measurement and Testing Techniques*", Springer Publishing, New York, NY, **2018**. http://www.springer.com/us/book/9783319696720. This book provided a comprehensive overview of the state-of-the-art contactless probing techniques and addressed a gap in chip testing literature.
3. Sayil, S., "*Soft Error Mechanisms, Modeling and Mitigation*", Springer Publishing, New York, NY, **2016**. http://www.springer.com/us/book/9783319306063. This text includes collection of my research during 2008-2016 and received very positive reviews which were published in a book review - "Microelectronics Reliability" journal, vol. 74, pg. 81, 2017.

BOOK CHAPTER PUBLICATIONS

1. **"VLSI: Circuits for Emerging Applications"**
   Publisher: CRC Press, October 24, 2014, *ISBN:* 978-1-4665-9909-3 (Hardcover)

   Chapter 13.3 – Selahattin Sayil, Lamar University
   Title: "Soft-Error-Aware Power Optimization Using Dynamic Threshold" (pp. 295–310)
   This book includes contributions from internationally recognized experts in industry and academia. Some authors are affiliated with companies such as IBM, Texas Instruments, and Intel. Academic contributors represent institutions from Japan, France, the UK, Germany, Italy, and top U.S. universities.

2. **"Advanced Circuits for Emerging Technologies"**
   Publisher: Wiley, May 2012, *ISBN:* 978-0-470-90005-0 (Hardcover)

   Chapter 23 – "Contactless Testing and Diagnosis Techniques" (pp. 581–597)
   This book is authored by leading international experts from industry and academia. Contributors include professionals from IBM, Texas Instruments, Broadcom, and Synopsys.

REFEREED JOURNAL PUBLICATIONS:

Published 30 peer-reviewed journal papers (mostly international) at Lamar. Most of the papers include Lamar Students as co-authors (shown as underlined).

1. Lamichhane, S., Wang, Y. & Sayil, S. "Mitigating soft errors in NCL circuits using a transmission gate", *Analog Integrated Circuits and Signal Processing*, vol. 115, pp. 101–109, **2023**.
2. Sayil, S., Lamichhane, S., Sayil, K. "Crosstalk noise mitigation using a transmission gate with varied gate bias", *Analog Integrated Circuits and Signal Processing*, vol. 105, pp. 183–190 **2020**.
3. Sayil, S., "A survey of circuit-level soft error mitigation methodologies", *Analog Integrated Circuits and Signal Processing*, vol. 99, no. 1, pp. 63-70, April **2019**.
4. Sayil, S., Bhowmik, P. "Mitigating the thermally induced single event crosstalk", *Analog Integrated Circuits and Signal Processing*, vol. 92, no. 2, pp. 247–253, August **2017**.
5. Sayil, S., Shah, A.H. , Zaman, M.A., Islam, M.A.,"Soft Error Mitigation using Transmission Gate with varying Gate and Body Bias", *IEEE Design and Test*, vol. 34, no. 1, pp. 47-56 , Feb. **2017**.
6. Sayil, S., Yao, Y., "Single Event Coupling Delay Estimation in Nanometer Technologies", *Analog Integrated Circuits and Signal Processing*, vol. 86, no:2, pp. 215-225, February **2016**.
7. Sayil, S., Yuan, Li, "Modeling Single Event Crosstalk Speedup in Nanometer Technologies", *Microelectronics Journal*, Volume 46, Issue 5, pp. 343–35, May **2015**
8. Sayil, S., Wang, J., "Coupling Induced Soft Error Mechanisms in Nanoscale CMOS technologies", *Analog Integrated Circuits and Signal Processing*, Volume 79, Issue 1, pp. 115-126, April **2014**.
9. Sayil, S., Wang, J. Yeddula, S. R., "Single Event Coupling Soft Errors in Nanoscale CMOS Circuits", *IEEE Design and Test*, Volume 30, Issue: 6, pp. 1-9, December **2013**.
10. Sayil, S., Boorla, V. K., "Single Event Crosstalk Prediction in Nanometer Technologies" *Analog Integrated Circuits and Signal Processing*, Volume 72, Issue 1, pp 205-214, July **2012**
11. Sayil, S., Wang, J., "Single Event Soft Errors in CMOS Logic", *IEEE Potentials*, Volume: 31, Issue: 2, Page(s): 15 – 22, April **2012**
12. Sayil, S., Boorla, V.K.,Yeddula, S.R., "Modeling Single Event Crosstalk in Nanometer Technologies", *IEEE Transactions on Nuclear Science*, Volume: 58 , Issue: 5 , Part: 2, pp. 2493 – 2502, October **2011**.
13. Sayil, S., Patel, N. B., "Soft Error and Soft Delay Mitigation using Dynamic Threshold Technique", *IEEE Transactions on Nuclear Science*, Volume: 57, Issue: 6, Part: 1, Dec. **2010**.
14. Sayil, S., Akkur, A.B., "Mitigation for single event coupling delay", *International Journal of Electronics*, Volume 97, Issue 1, pages 17 – 29, January **2010**.
15. Sayil, S., Akkur, A.B., Gaspard, N., "Single Event Crosstalk Shielding for CMOS Logic", *Microelectronics Journal*, vol. 40, no. 6, 1000-1006, **2009**.

16. Sayil, S., Borra, U. K., "Coupling Delay Calculation Using Miller Factors under Exponential Waveforms", *International Journal of Electronics*, vol. 96, no. 4, pp. 351 – 366, April **2009**.
17. Sayil, S., Borra, U. K., "A Multiline Model for Time-Efficient Estimation of Crosstalk", *Analog Integrated Circuits and Signal Processing*, vol. 59, no. 1, pp. 65 – 75, **2009**.
18. Sayil, S., "On the Use of Silicon Photonics- Part I", *IEEE Potentials*, vol. 28, no. 1, pp. 35 – 39, January-February **2009**.
19. Sayil, S., "On the Use of Silicon Photonics- Part II", *IEEE Potentials*, vol. 28, no. 2, pp. 37 – 40, March-April **2009**.
20. Sayil, S., Rudrapati, M., "Accurate Prediction of Crosstalk for RC Interconnects", *Turkish Journal of Electrical Engineering* (included in the Science Citation Index Expanded), Volume 17, Issue 1, pp. 55-67, **2009**.
21. Sayil, S., "Avalanche Breakdown in Silicon Devices for Contactless Logic Testing and Optical Interconnect", *Analog Integrated Circuits and Signal Processing*, Volume 56, No. 3, pp. 213-221, 2008.
22. Borra, U. K., Sayil, S., "Coupling Noise and Delay Estimation under Exponential type Waveforms", *Electronic Journal of Student Research*, Lamar Univ., Volume IX, Fall 2008.
23. Gaspard, N., Sayil, S., "Single Event Transient Crosstalk Interconnect Shielding to Complete SEU hardening of CMOS Logic Gates", *Electronic Journal of Student Research*, Lamar Univ., Volume VIII, Summer 2008.
24. Sayil, S., Rudrapati, M., "Precise Estimation of Crosstalk in Multiline Circuits", *International Journal of Electronics*, Vol. 94, No. 4, pp. 413 – 429, April 2007.
25. Sayil, S., "Optical Contactless Probing: An All-Silicon, Fully Optical Approach," *IEEE Design and Test of Computers*, vol. 23, no. 2, pp. 138-146, Mar/Apr, 2006-Special Feature Article
26. Anita, M., Sayil, S., "Time-Efficient Estimation of Crosstalk in Multi-Line Circuits", *Electronic Journal of Student Research,* Lamar Univ.", Volume III, Spring 2006.
27. Sayil, S., Kerns, D.V., Kerns, Sherra E., "A Survey of Contactless Measurement and Testing Techniques", *IEEE Potentials*, Published on Feb/March 2005 issue, pp. 25-28
28. Sayil, S., Kerns, D.V., Kerns, Sherra E. "Comparison of Contactless Measurement and Testing Techniques to a new All-Silicon Optical Test and Characterization Method", *IEEE Transactions on Instrumentation & Measurement*, Vol. 54, No. 5, pp. 2082-2089, October 2005.
29. Sayil, S., Kerns, D.V., Kerns, Sherra E. "All-Silicon Optical Contactless Testing of Integrated Circuits" *International Journal of Electronics* vol.89, no. 7 p.537-547, July 2002.
30. Sayil, S. "A Combine Algorithm for a CMAC Network", *PAU Journal of Engineering Science,* vol.7, no. 4, 2001.

PEER REVIEWED CONFERENCE/SYMPOSIUM PRESENTATIONS

Almost all conference papers included Lamar students as co-authors.

1. Wang, Y. and Sayil, S. "Soft Error Evaluation and Mitigation in Gate Diffusion Input Circuits," 2024, IEEE 6th International Conference on Power, Intelligent Computing and Systems (ICPICS), Shenyang, China, pp. 121-128, doi: 10.1109/ICPICS62053.2024.10796093, **2024**.
2. Tcheslavski, G., Yoo, J., and Sayil, S. (2024), Implementing Collaborative Online Lab Experiences to Facilitate Active Learning Paper presented at 2024 ASEE Annual Conference & Exposition, Portland, Oregon. 10.18260/1-2-47580, **2024**.
3. S. Sayil, G. Tcheslavski, J. Yoo and Y. Wang, "Online Electrical Engineering Labs with Collaborative Open-Ended Assignments," 2023 IEEE Frontiers in Education Conference (FIE), College Station, TX, USA, **2023**.
4. Yoo, J., Sayil, S., & Tcheslavski, G. (2023), "Achieving Active Learning through Collaborative Online Lab Experiences", 2023 ASEE Annual Conference & Exposition , Baltimore, MD, **2023**
5. S. Sayil, J. Yoo and G. Tcheslavski, "Creating Engaged and Active Learning Through Collaborative Online Lab Experiences," 2022 *IEEE Frontiers in Education Conference* (FIE), Uppsala, Sweden, **2022**.
6. S. Sayil, "Enhancing Student Learning via Hardware in Homework", 2021 ASEE Virtual Annual Conference, https://peer.asee.org/37086, **2021**.
7. Sayil, S., Lamichhane, S., Sayil, K., "Coupling Noise Mitigation using a Pass Transistor," 2020 IEEE Computer Society Annual Symposium on VLSI (ISVLSI), Limassol, Cyprus, **2020**, pp. 358-362.
8. Sayil, S., "Compensation of Thermally-Induced Soft Errors using Forward Body-Bias", Presented at 25th Annual *Single Event Effects (SEE)/MAPLD Symposium*, San Diego, May **2016**.
9. Rahman, Md. M., Bhowmik, P., Sayil, S., "Mitigation of Thermally Induced Crosstalk Noise by Dynamically Adjusting Driver Strength", *2nd International Conference on Electrical Information and Communication Technology* (*EICT 2015*), **2015**.
10. Sayil, S., Yao, Yao, "Predicting Single Event Coupling Delay in Nanometer Technologies", Presented at 24th Annual *Single Event Effects (SEE)/MAPLD Symposium*, San Diego, May 2015.
11. Sayil, S., Yao Y., Islam, Md. A, "Soft Error Mitigation Using Transmission Gate with Varying Gate and Body Bias", Presented in *2014 IEEE Nuclear and Space Radiation Effects Conference,* July 2014, Paris, France.
12. Sayil, S., Boorla, V. K., "Modeling Single Event Crosstalk in Nanometer Technologies", Presented in *International Conference on Electrical and Electronics Engineering,* ELECO'11, 7-11 Nov, Bursa, Turkey.
13. Sayil, S., Patel, N., "Soft Error and Soft Delay Mitigation using a Dynamic Threshold Scheme", Presented in *2010 IEEE Nuclear and Space Radiation Effects Conference*, Denver, CO.
14. Sayil, S., Rudrapati, M. S., Borra, U. K., "An Improved Multiline model for Precise Estimation of Crosstalk", Presented in *2007 IEEE Region 5 Technical Conference*, pp. 239-245, April 20-21, Fayetteville, AR

15. Sayil, S., "On the Use of Silicon Photonics for Optical Interconnect and Contactless Logic Testing", *2007 IEEE Region 5 Technical Conference*, pp. 42-48, April 20-21, Fayetteville, AR.
16. Sayil, S., Lee, K.Y. "An Hybrid Neighborhood Training and Maximum Error Algorithm for CMAC", Proceedings of the 2002 *World Congress on Computational Intelligence*, 5,31 2002.
17. Sayil, S., Kerns, D.V., Kerns, Sherra E., "All-Silicon Optical Technology For Contactless Testing Of Integrated Circuits", Proceedings of the *International Conference on Electrical and Electronics Engineering ELECO'01*, 7-11 Nov, Bursa, Turkey.

SECURED FUNDING:

As a PI, I have secured **4 External**, **9 Internal grants** and 7 course development grants which supported our students. The total amount of funding obtained is $401,713. Below is an incomplete list:

EXTERNAL GRANTS AND DONATIONS:

(1) **Sayil, S.** (**PI**), Tcheslavski, G. (co-PI) and Yoo, Julia (co-PI), "*Promoting engaged and active learning through collaborative online lab experiences*", **NSF** Improving Undergraduate STEM Education (IUSE) program, Funding period" Sept. 1, 2021- Aug. 31, 2024, **$294,097**.

(2) **Sayil, S.** (**PI**), (no co-PI), "Project Title: Enhancing Student Learning via Value Added Engineering Education (VAEE)", *Academic Partnerships*, Fall 2015, Funding Period: 11/20/2015- 6/30/2016, **$4,116** .

(3) **Sayil, S.** (**PI**), Myler, H. R. Co-PI, "Space Radiation Effects on Technology and Human Biology and Proper Mitigation Techniques", NASA/ **Texas Space Grant Consortium (TSGC) Higher Education**, March 2008, September 2008-August 2010, **$15,000.**

(4) **Sayil, S.** (**PI**), (no co-PI), "Low Power Radiation Tolerant VLSI Design for Advanced Spacecraft", Texas Space Grant Consortium (TSGC) / NASA New Investigations Program (NIP), October 2010, PI, **$9,000.**

(5) **Synopsys University Tool Package donation** from Synopsys-Sponsored University Software Program – renewed three times (2022–2025), in-kind value $4,500 (3-year period).

(6) **DE1-SoC FPGA donation** (8 units) from Intel FPGA Program, in-kind value $3,000.

INTERNAL GRANTS:

(1) **Sayil, S.** (**PI**), (no co-PI), "Project Title: A Circuit-Based Approach for Compensation of Thermally-Induced Soft Errors in Microchips", Lamar Research Enhancement Grant, Fall 2016, $5,000.

(2) **Sayil, S.** (**PI**), (no co-PI), "Project Title: Studying the Impact of Temperature on Microchip Radiation Tolerance", Lamar Research Enhancement Grant, Spring 2014, $5,000.

(3) **Sayil, S.** (**PI**), (no co-PI), "Mitigation of Radiation Induced Transients in Advanced Microchips using Transmission Gate with Varying Input Voltage", Lamar Research Enhancement Grant, Spring 2012, PI, $5,000.

(4) **Sayil, S.** (**PI**), (no co-PI), "Studying the Impact of Power Optimizations on Microchip Radiation Tolerance", Lamar Research Enhancement Grant, Spring 2010, $5,000.

(5) **Sayil, S.** (**PI**), (no co-PI), "Modeling the Effect of Ionizing Radiation on Circuit Delay for Today's Advanced Microchip Technologies", Lamar Research Enhancement Grant, Spring 2009, $5,000.

(6) **Sayil, S., PI**, (no co-PI), "The Impact of Radiation Induced Single Event Upsets on Cross-talk Noise for Today's Advanced Microchip Technologies", Lamar Research Enhancement Grant, Spring 2007, $5,000.

(7) **Sayil, S., PI**, (no co-PI), "Modeling the Impact of Cross-Coupling Noise on Wire Delay for Today's Microchip Technologies", Lamar Research Enhancement Grant Proposal – Spring 2006, $5,000.

(8) **Sayil, S., PI**, (no co-PI), "Evaluation of Existing Test Sets for Crosstalk Test Coverage using VHDL Hardware Description Language", Lamar Research Enhancement Grant – Spring 2004, $5,000.

(9) **Sayil, S., PI**, (no co-PI), "A New Time-Efficient Method for Precise Estimation of Cross-talk Noise on Multi-line Circuits", Lamar Research Enhancement Grant – Fall 2003, $5,000.

COURSE DEVELOPMENT GRANTS OBTAINED:

(1) Lamar University Online Course Development Grant, for preparing the undergraduate course titled "ELEN 2411-48F Circuits I and Lab", $6,000.

(2) Lamar University Online Course Development Grant, for preparing the undergraduate course titled "ELEN 3322-48F Electronics II", $4,500.

(3) Lamar University Online Course Development Grant, for preparing the Summer 15 graduate course titled "ENGR 4301/5301-48F Low Power CMOS Design and Reliability", $4,500.

(4) Lamar University Online Course Development Grant, for preparing the Summer 15 graduate course titled "ELEN 4304/5301-49F VLSI Design and CAD Tools", $4,500.

(5) Lamar University Online Course Development Grant, for preparing the Fall 15 undergraduate course titled "ELEN 3421-48F Electronics I", $6,000.

(6) Lamar University Online Course Development Grant, for preparing the Fall 15 graduate course titled "ENGR 4324/5324-48F CMOS Digital IC Design", $4,500.

(7) Lamar University Online Course Development Grant, for preparing the Fall 15 graduate course titled "ENGR 4304 Topics in VLSI", $4,500.

DEVELOPMENT OF COURSES, CURRICULA, AND OTHER TEACHING ACTIVITIES

- **Books:** Authored 3 books in VLSI/Microelectronics with Springer Publishing.

- **Grant Funding:**

  - PI, NSF IUSE Grant ($294,097) to implement active learning in Electrical Engineering online labs.

- PI, Academic Partnerships Educational Grant supporting Value Added Engineering Education (VAEE).
- PI, NASA TSGC Higher Education Program grant for **Space Radiation Effects & Mitigation** course development.

Course and Lab Development:

- Integrated active learning strategies (open-ended labs, virtual teamwork, pre-lab simulations/videos, online communities) into 3 ECE courses.
- Developed 2 experimental online lab modules for higher education and high school STEM students; publicly available at https://sites.google.com/view/active-learning-online-labs. While the first module specifically was tailored for higher education institutions featuring a diverse range of electrical engineering online lab experiments, including open-ended labs, the 2nd module titled STEM module targeted high school students.
- Teaching innovation: Integrated lab experiences into purely theoretical courses via Value Added Engineering Education (VAEE) concept. The project aimed at promoting deeper learning in theory courses.
- Online Leadership: Created and taught first departmental online course (**Fundamentals of Electrical Engineering**, 2012) and first online lab course (2014).
- Biggest contributor to our Digital eLearning Content Delivery program: Developed 12 online courses (4 undergraduate, 6 graduate/elective, 2 lab), all Quality Matters (QM) certified.
- Designed 6 graduate courses in VLSI Design and Signal Integrity; established VLSI CAD and Signal Integrity Lab supporting doctoral specialization.
- Taught a total 33 different courses at both undergraduate and graduate levels at Lamar and supervised about 40 Master's Theses and 3 Doctoral students.

Outreach and Professional Development:

- Organized webinars for high school STEM teachers on enhanced lab practices and **lab-in-a-box** implementation.

Mentorship and Supervision:

- Supervised 30+ Master's theses and 3 doctoral dissertations.
- Mentored two Senior Students for IEEE Paper Competition. Both papers won 1st place awards in IEEE Region V East area competition and IEEE Beaumont section.
- Offered 12 research-oriented independent study courses.

Publication with Students:

- Published 30 journal articles and numerous conference papers with student serving as co-authors in most publications.

TEACHING RELATED SERVICE (incomplete list)

- Graduate Student Advisor (2024 -) Advised more than 200 students
- Associate Editor for Intl Journal of Electronics (2008-present)
- Mentored Lamar IEEE Student Branch for 12-years (2003-2015).
- Department ABET Accreditation coordinator 2015-2022: Prepared ABET self-study report for our "Digital eLearning Content Delivery".
- Department's SACS Representative 2009-2021: Preparer of instructional effectiveness report and plan.
- Served as Faculty senator (twice) and Dean Search Committee member (2019),Member of DE Program Review Committee, PIR and Distance Education Committee (twice)
- Proposal Reviewer (Panel Member) for NASA/TSGC New Investigations Program 2013-invited.
- Judge for IEEE Region 5 student paper competition (2011) and LU IEEE paper competition (every year)
- Textbook and Manuscript Reviewer: Reviewed more than 12 engineering books, Manuscript reviewer (more than 100 journals)

PROFESSIONAL DEVELOPMENT ACTIVITIES (Incomplete List)

(Workshop, Short Course, Conferences Attended)

1. ASEE Gulf Southwest Section member
2. Attended 2023 FIE Conference
3. Attended 2022 FIE Conference
4. Attended 2022 AAAS-IUSE STEM Learning through Community Engagement Webinar
5. 2022 Southeast Symposium on Contemporary Engineering Topics (SSCET)
6. 2022 Improving Undergraduate STEM Education (IUSE) National Summit
7. Attended 2021 ASEE Conference
8. Attended ECEDHA Webinar titled "Modern Lab for Remote Learning: Hands-On Real-Time Digital Signal Processing Using Low-Cost Portable Hardware", 4/22/21
9. Writing/Designing Winning NSF Proposals Workshop January 25, 2016
10. 25th Annual *Single Event Effects (SEE) Symposium*, and *Military and Aerospace Programmable Logic Devices* (*MAPLD*) Workshop, San Diego, May 2016.
11. 24th Annual *Single Event Effects (SEE) Symposium*, and *Military and Aerospace Programmable Logic Devices* (*MAPLD*) Workshop, San Diego, May 2015.
12. 2014 *Nuclear and Space Radiation Effects* (*NSREC*) *Radiation Effects Data Workshop*, Paris, France.

13. 2014 *Nuclear and Space Radiation Effects* (*NSREC*) *Conference*, Paris, France.
14. *National Science Foundation (NSF) one-day workshop*" at Texas A&M University- Commerce, November 14, 2011.
15. 7th *International Conference on Electrical and Electronics Engineering* ELECO, Conference, Bursa, TURKEY, Dec. 1-3, 2011.
16. 2010 *Nuclear and Space Radiation Effects* (*NSREC*) *Short Course*, Denver, CO
17. 2010 *Nuclear and Space Radiation Effects* (*NSREC*) *Conference*, Denver, CO.
18. 2010 *Nuclear and Space Radiation Effects* (*NSREC*) *Radiation Effects Data Workshop*, Denver, CO.
19. *NSF Power Electronics Workshop*, and "*Successful Grant Writing" Seminar*, 2004.
20. *NSF Educational Grant workshop* on "Successful Grant Writing", Lamar University, Beaumont, TX 2005.
21. *ABET workshop* in Baltimore on Assessing Program Outcomes, 2007.